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Micron Technology, Inc.FILING DATE  
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## U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA					
	AB					
	AC					
	AD					

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

VN	AE	S/N: 09/032,184; Filed 2/27/98; Akram et al.; Amendment filed 12/18/00; CPA filed 7/28/00; Amendment filed 3/3/00; Amendment filed 8/23/99;
		Original Application filed 2/27/98; Pending Claims.
VN	AF	Advertisement for Probe Technology; <a href="http://www.idinet.com">www.idinet.com</a> ; Interconnect Devices, Inc.; 1 page; 3/6/98
VN	AG	Good Things Come In Small BGA/CSP Packages; <a href="http://www.johnstech.com/4/handbook/page9.html">www.johnstech.com/4/handbook/page9.html</a> ; 1 page; 3/5/98
VN	AH	Product Description for Double Ended Probes, B1052 Series; <a href="http://www.testprobe.com/products/b1052.html">www.testprobe.com/products/b1052.html</a> ; Rika Denshi America, Inc.; 1 page; 2/4/98.
VN	AI	Product Description for Test Centers, RM-500 Series Probes, <a href="http://www.testprobe.com/products/rm500.html">www.testprobe.com/products/rm500.html</a> ; Rika Denshi America, Inc.; 1 page; 2/4/98.
VN	AJ	Product Description for Cost Effective Interconnections for High I/O Products; <a href="http://www.testprobe.com/products/io.htm#b1303">www.testprobe.com/products/io.htm#b1303</a> ; Rika Denshi America, Inc.; 1 page; 2/4/98.
VN	AK	Product Description for Ball Grid Probe B1303-C3; <a href="http://www.testprobe.com/products/io.htm#b1303">www.testprobe.com/products/io.htm#b1303</a> ; Rika Denshi America, Inc.; 1 page; 2/4/98.
VN	AL	Product Description for Test Socket Contacts; <a href="http://www.johnstech.com/4/handbook/page9.html">www.johnstech.com/4/handbook/page9.html</a> ; 1 page; 3/5/98

EXAMINER

*rukh Nguyen*

DATE CONSIDERED

10/25/2001

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.